L Number	Hits	Search Text	DB	Time stamp
1	11	"5012105"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:32
2	3002	(250/492.22,492.2,492.23).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:33
3	3501	(250/492.22,492.2,492.23,398).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:34
4	8190	multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:36
5	185	(multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam or sub-beam)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:36
6	112	((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam or sub-beam)) and aperture	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:37
7	71	(((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam or sub-beam)) and aperture) and deflect$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:37
8	10	((((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam or sub-beam)) and aperture) and deflect$4) and (different with pattern)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:38
9	46	((((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam or sub-beam)) and aperture) and deflect$4) and simultan$8	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:39
10	33	(((((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam or sub-beam)) and aperture) and deflect$4) and simultan$8) and independent$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:45
11	45	(((((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam or sub-beam)) and aperture) and deflect$4) and simultan$8) and (independent$3 or individual$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:52
12	7	((((((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam or sub-beam)) and aperture) and deflect$4) and simultan$8) and (independent$3 or individual$4)) and ((250/492.22,492.2,492.23,398).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:51

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13	17	(((((multibeam or multi-beam or (multiple adj (aperture or beam or beamlet)) and (electron or charged-particle or (charged adj particle))) and (beamlet or subbeam or sub-beam)) and aperture) and deflect$4) and simultan$8) and ((independent$3 or individual$4) with deflect$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 13:53
14	9	"5359202"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 14:01
15	11	"5841145"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 14:03
16	10	"5977548"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 14:04

L Number	Hits	Search Text	DB	Time stamp
1	556	((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:37
2	31	(((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (beamlet or subbeam or sub-beam)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
3	26	((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (beamlet or subbeam or sub-beam)) and (different$4 near4 (imag$5 or pattern$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
4	24	(((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (beamlet or subbeam or sub-beam)) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
5	19	((((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (beamlet or subbeam or sub-beam)) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5) and (etch$3 or writing or lithograph$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:05
6	353	(((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:05
7	162	((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:06
8	118	(((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5) and (etch$3 or writing or lithograph$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:39
9	32	((((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5) and (etch$3 or writing or lithograph$3)) and ((independent$3 or individual$4) with deflect$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:39

10	0	09/375627	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:28
11	0	(09/375627).CCLS.	USPAT; US-PGPUB; EPO; DERWENT	2003/10/17 16:28
12	7	"375627"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:28
13	2	Hans adj Loschner	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:29
14	2	5637951.URPN.	USPAT	2003/10/17 16:34
15	6	("4675572" | "4940916" | "4990766" | "5103144" | "5363021" | "5528103").PN.	USPAT	2003/10/17 16:35
16	606	((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:37
17	31	(((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (beamlet or subbeam or sub-beam)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
18	380	(((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
19	171	((((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
20	127	(((((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5) and (etch$3 or writing or lithograph$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:39

| 21 | 39 | (((((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5) and (etch$3 or writing or lithograph$3)) and ((independent$3 or individual$4) with deflect$5) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/10/17 16:39 |
| 22 | 34 | ((((((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5) and (etch$3 or writing or lithograph$3)) and ((independent$3 or individual$4) with deflect$5)) and aperture | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/10/17 16:49 |

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L Number	Hits	Search Text	DB	Time stamp
1	556	((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:37
2	31	(((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (beamlet or subbeam or sub-beam)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
3	26	((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (beamlet or subbeam or sub-beam)) and (different$4 near4 (imag$5 or pattern$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
4	24	(((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (beamlet or subbeam or sub-beam)) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
5	19	((((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (beamlet or subbeam or sub-beam)) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5) and (etch$3 or writing or lithograph$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:05
6	353	(((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:05
7	162	((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:06
8	118	(((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5) and (etch$3 or writing or lithograph$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:39
9	32	((((((multiple adj (beam or aperture)) or multibeam or multi-beam) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5) and (etch$3 or writing or lithograph$3)) and ((independent$3 or individual$4) with deflect$5)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:39

10	0	09/375627	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:28
11	0	(09/375627).CCLS.	USPAT; US-PGPUB; EPO; DERWENT	2003/10/17 16:28
12	7	"375627"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:28
13	2	Hans adj Loschner	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:29
14	2	5637951.URPN.	USPAT	2003/10/17 16:34
15	6	("4675572" | "4940916" | "4990766" | "5103144" | "5363021" | "5528103").PN.	USPAT	2003/10/17 16:35
16	606	((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:37
17	31	(((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (beamlet or subbeam or sub-beam)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
18	380	(((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
19	171	((((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:38
20	127	(((((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5) and (etch$3 or writing or lithograph$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 16:39

| 21 | 39 | (((((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5) and (etch$3 or writing or lithograph$3)) and ((independent$3 or individual$4) with deflect$5) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/10/17 16:39 |
| 22 | 34 | (((((((multiple adj (beam or aperture)) or multibeam or multi-beam or multi-electron or multielectron) and (electron or charged-particle or (charged adj particle)) and (different$4 with (imag$5 or pattern$4))) and (different$4 near4 (imag$5 or pattern$4))) and (independent$3 or individual$4) and deflect$5) and (etch$3 or writing or lithograph$3)) and ((independent$3 or individual$4) with deflect$5)) and aperture | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/10/17 16:49 |

L Number	Hits	Search Text	DB	Time stamp
1	1966	(mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3 and pattern$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:25
2	696	((mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3 and pattern$3) and ((different or var$5) near4 (pattern$4 or imag$5))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 17:58
3	449	(((mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3 and pattern$3) and ((different or var$5) near4 (pattern$4 or imag$5))) and aperture	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 17:59
4	627	(((mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3 and pattern$3) and ((different or var$5) near4 (pattern$4 or imag$5))) and (individual$4 or independent$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:01
5	30	l14 and (etch$4 or writing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:01
6	2905	(mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:15
7	268	((mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3) and lithograph$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:04
8	180	(((mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3) and lithograph$3) and (electron or ion or charged-particle or (charged adj particle))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:06
9	830	((mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3) and (electron or ion or charged-particle or (charged adj particle))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:06
10	165	(mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and ((etch$4 or writ$4) near4 (different or vari$5))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:11
11	830	(mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3 and (electron or ion or charged-particle or (charged adj particle))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:20
12	744	((mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3 and (electron or ion or charged-particle or (charged adj particle))) and different	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:21
14	0	((((mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3 and (electron or ion or charged-particle or (charged adj particle))) and different) and pattern$3) and abberration	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:22

13	549	(((mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3 and (electron or ion or charged-particle or (charged adj particle))) and different) and pattern$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:22
15	402	(mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3 and (different near2 (image or pattern$3))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:28
16	9	((mulitbeam or mulit-beam or multi-aperture or multi-aperture or (multiple adj beam)) and simultaneous$3 and (different near2 (image or pattern$3))) and ((writ$3 or etch$4) with(different near2 (image or pattern$3)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/10/17 18:29